| | Туре | L# | Hits | Search Text | DBs | Time Stamp | Comments | Error Definition | Errors |
|---|------|----|---------|---|---|---------------------|----------|---------------------|--------|
| 1 | BRS | L1 | 11930 | ("gate electrode" or transitor) same ((oxide or "SiO.sub.2") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:12 | · | | |
| 2 | BRS | L2 | 23250 | ("gate electrode" or transistor) same ((oxide or "SiO.sub.2") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:15 | | | |
| 3 | BRS | L3 | 12150 | | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:16 | - | | |
| 4 | BRS | L4 | ארננו | electrode" or transistor)) same ((oxide or "SiO.sub.2") with | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:19 | | | |
| 5 | BRS | L5 | 1578 | 4 and @pd<="20000320" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:19 | | | |
| 6 | BRS | L6 | | electrode" or transistor)) same ((oxide or "SiO.sub.2") adj3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:20 | | | |
| 7 | BRS | L7 | 208 | 6 and @pd<="20000320" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:22 | | | |
| 8 | BRS | L8 | 7113311 | ((oxide or "SiO.sub.2") adj3 (dop\$3 or implant\$5)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:08 | | | |

| | Type | L# | Hits | Search Text | DBs | Time Stamp | Comments | Error Definition | Errors |
|----|------|-----|-------|---|---|---------------------|----------|---------------------|--------|
| 9 | BRS | L9 | 13622 | ((oxide or "SiO.sub.2") adj2 (dop\$3 or implant\$5)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:29 | | | |
| 10 | BRS | L10 | 6514 | ((oxide or "SiO.sub.2") adj (dop\$3 or implant\$5)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:21 | | · | |
| 11 | BRS | L11 | 187 | ((sidewall) same ("gate electrode" or transistor)) same 9 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:22 | | | |
| 12 | BRS | L12 | 90 | 11 and @pd<="20000320" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 13:30 | | | · |
| 13 | BRS | L13 | 4926 | 9 and (transistor or FET or "gate electrode") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:09 | | | |
| 14 | BRS | L14 | 2144 | 13 and @pd<="20000320" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:09 | | | |
| 15 | BRS | L15 | 3044 | ((oxide or "SiO.sub.2") adj3 (doping or implanting)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:10 | | | |
| 16 | BRS | L16 | 1721 | 15 and (transistor or FET or "gate electrode") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 16:46 | | | |

| | Туре | L# | Hits | Search Text | DBs | Time Stamp | Comments | Error Definition | Errors |
|----|-------|-----|------|--|---|---------------------|----------|---------------------|--------|
| 17 | BRS | L17 | 911 | 16 and @pd<="20000320" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:11 | | • | |
| 18 | BRS | L18 | 1791 | ((oxide or "SiO.sub.2") adj2 (doping or implanting)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 16:36 | | | |
| 19 | BRS | L19 | 920 | 18 and (transistor or FET or "gate electrode") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2004/11/30 14:11 | | | |
| 20 | BRS | L20 | 505 | 19 and @pd<="20000320" | HPCF IPCF | 2004/11/30 16:47 | | | |
| 21 | BRS | L21 | 420 | (deposit\$3 or form\$3) with (oxide or "SiO.sub.2") with (non adj (uniform\$2 or conform)) | | 2004/11/30 16:37 | | | |
| 22 | BRS | L22 | 166 | "nate electrode") | ILLO, JLO, I | 2004/11/30 16:46 | | | |
| 23 | BRS I | _23 | 37 | 22 and @pd<="20000320" | PPU IPU I | 2004/11/30 16:47 | | | |